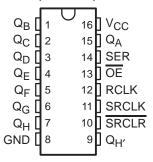
SCLS374F - MAY 1997 - REVISED JANUARY 2000

- EPIC[™] (Enhanced-Performance Implanted CMOS) Process
- Inputs Are TTL-Voltage Compatible
- 8-Bit Serial-In, Parallel-Out Shift
- Shift Register Has Direct Clear
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

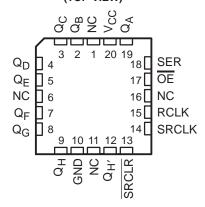
description

The 'AHCT595 devices contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state outputs. Separate clocks are provided for the shift and storage registers. The shift register has a direct overriding clear (\overline{SRCLR}) input, serial (SER) input, and serial outputs for cascading. When the output-enable (\overline{OE}) input is high, the outputs are in the high-impedance state.

SN54AHCT595 . . . J OR W PACKAGE SN74AHCT595 . . . D, DB, N, OR PW PACKAGE (TOP VIEW)



SN54AHCT595...FK PACKAGE (TOP VIEW)



NC - No internal connection

Both the shift register clock (RCLK) and storage register clock (SRCLK) are positive-edge triggered. If both clocks are connected together, the shift register always is one clock pulse ahead of the storage register.

The SN54AHCT595 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74AHCT595 is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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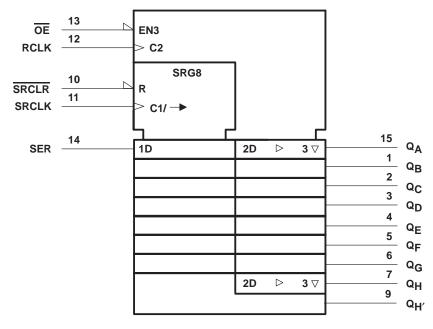
SN54AHCT595, SN74AHCT595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS

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FUNCTION TABLE

		INPUTS			FUNCTION
SER	SRCLK	SRCLR	RCLK	OE	FUNCTION
Х	Х	Х	Х	Н	Outputs Q _A –Q _H are disabled.
Х	Χ	Χ	Χ	L	Outputs Q _A –Q _H are enabled.
Х	Χ	L	X	Χ	Shift register is cleared.
L	1	Н	Х	Х	First stage of the shift register goes low. Other stages store the data of previous stage, respectively.
Н	1	Н	Х	Х	First stage of the shift register goes high. Other stages store the data of previous stage, respectively.
Х	\downarrow	Н	Х	Χ	Shift-register state is not changed.
Х	X	Χ	\uparrow	Χ	Shift-register data is stored into the storage register.
Х	X	Χ	\downarrow	Χ	Storage-register state is not changed.

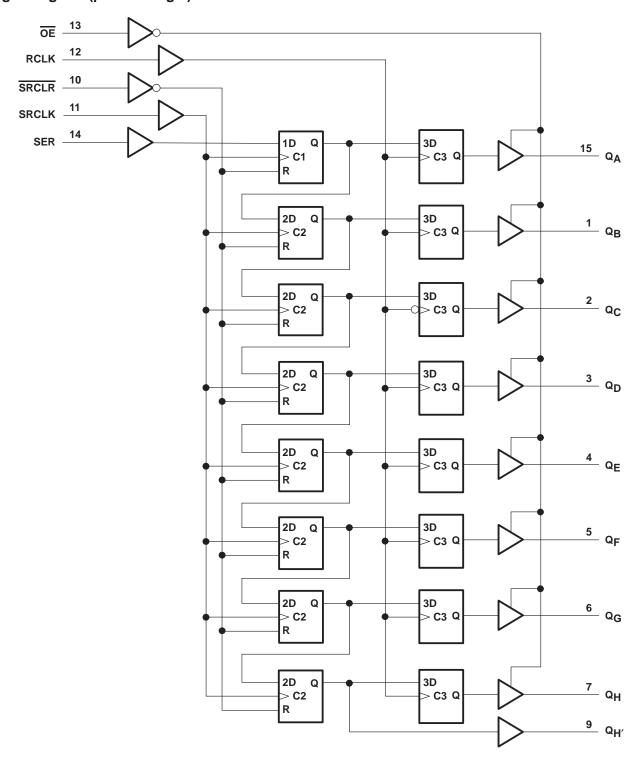
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, N, PW, and W packages.



logic diagram (positive logic)

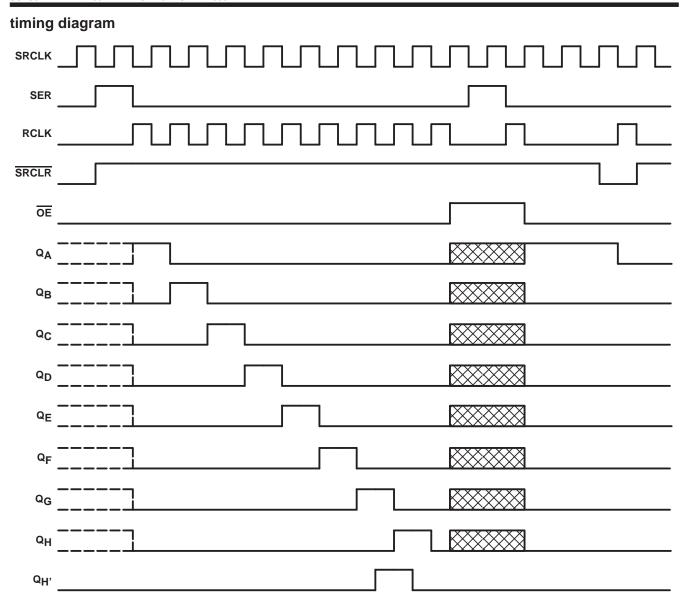


Pin numbers shown are for the D, DB, J, N, PW, and W packages.



SN54AHCT595, SN74AHCT595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Output voltage range, VO (see Note 1)		0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$)		–20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CO}$	c)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$		
Continuous current through V _{CC} or GND		
Package thermal impedance, θ _{JA} (see Note 2)	: D package	73°C/W
, ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		82°C/W
	N package	67°C/W
	PW package	108°C/W
Storage temperature range, T _{sta}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		SN54AHCT595		SN74AH	CT595	UNIT
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	7	2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0	VCC	0	VCC	V
ІОН	High-level output current	37	-8		-8	mA
loL	Low-level output current	70,	8		8	mA
Δt/Δν	Input transition rise or fall rate	Q	20		20	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN54AHCT595, SN74AHCT595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T,	λ = 25°C	;	SN54AF	CT595	SN74AH	CT595	UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Va.:	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
VOH	$I_{OH} = -8 \text{ mA}$	4.5 V	3.94			3.8		3.8		V
\/o:	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
VOL	I _{OL} = 8 mA	4.5 V			0.36		0.44		0.44	V
lį	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ
I _{OZ}	$V_O = V_{CC}$ or GND	5.5 V			±0.25	4	±2.5		±2.5	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4	22	40		40	μΑ
ΔI _{CC} †	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35	P. P.O.	1.5		1.5	mA
Ci	$V_I = V_{CC}$ or GND	5 V		3	10				10	pF
Co	$V_O = V_{CC}$ or GND	5 V		5.5	·		·			pF

 $^{^*}$ On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0 \text{ V}$.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T _A = 2	25°C	SN54AH	CT595	SN74AH	CT595	UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	UNII	
		SRCLK high or low	5		5.5		5.5			
t _W	t _W Pulse duration	RCLK high or low	5		5.5	TEV.	5.5		ns	
		SRCLR low	5		5	ZE T	5			
		SER before SRCLK↑	3		3,4	2	3			
	Catum times	SRCLK↑ before RCLK↑‡	5		5		5			
t _{su}	Setup time	SRCLR low before RCLK↑	5	55		5		ns		
		SRCLR high (inactive) before SRCLK↑	3.4		3.8		3.8			
t _h	Hold time	SER after SRCLK↑	2		2		2		ns	

[‡] This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.

[†] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or VCC.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	Վ = 25° C	;	SN54AH	ICT595	SN74AH	ICT595	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF	135*	170*		115*		115		MHz
f _{max}			C _L = 50 pF	95	140		85		85		IVII IZ
tPLH	DOLK	0 0	C _L = 15 pF		4.3*	7.4*	1*	8.5*	1	8.5	ns
^t PHL	RCLK	Q_A-Q_H	CL = 15 μι		4.3*	7.4*	1*	8.5*	1	8.5	115
^t PLH	CDCI IX	0	C _L = 15 pF		4.5*	8.2*	1*	9.4*	1	9.4	ns
^t PHL	SRCLK	Q _H ′	CL = 15 μι		4.5*	8.2*	1*	9.4*	1	9.4	115
^t PHL	SRCLR	$Q_{H'}$	C _L = 15 pF		4.5*	8*	1*	9.1*	1	9.1	ns
^t PZH	ŌĒ	0 0	C _I = 15 pF		4.3*	8.6*	1*	10*	1	10	ns
tPZL		Q_A-Q_H	C[= 15 pr		5.4*	8.6*	1*,4	10*	1	10	115
tPLH	DOLK	0 . 0	C _L = 50 pF		5.6	9.4	(ج)	10.5	1	10.5	ns
^t PHL	RCLK	Q _A –Q _H	CL = 30 pr		5.6	9.4	Q1	10.5	1	10.5	115
t _{PLH}	CDCI IX	0	C _I = 50 pF		6.4	10.2	g 1	11.4	1	11.4	ns
^t PHL	SRCLK	Q _H ′	CL = 30 pr		6.4	10.2	1	11.4	1	11.4	115
^t PHL	SRCLR	$Q_{H'}$	C _L = 50 pF		6.4	10	1	11.1	1	11.1	ns
^t PZH	ŌĒ	0 0	C: - 50 pF		5.7	10.6	1	12	1	12	no
tPZL] 05	Q_A-Q_H	C _L = 50 pF		6.8	10.6	1	12	1	12
t _{PHZ}	ŌĒ	0. 0	C: - 50 pF		3.5	10.3	1	11	1	11	no
t _{PLZ}	OE .	Q _A –Q _H	C _L = 50 pF		3.4	10.3	1	11	1	11	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, $V_{CC} = 5 \text{ V}$, $C_L = 50 \text{ pF}$, $T_A = 25^{\circ}\text{C}$ (see Note 4)

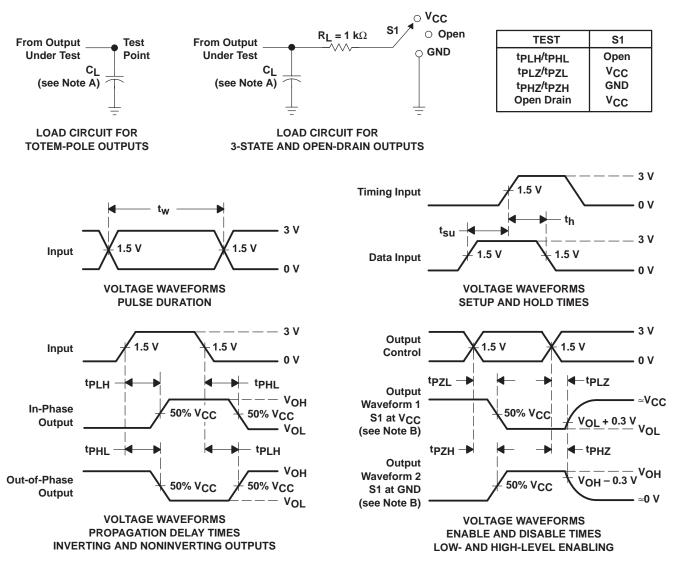
	PARAMETER		SN74AHCT595			
	FARAWEIER	MIN	TYP	MAX	UNIT	
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		1		V	
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.6		V	
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		3.8		V	
VIH(D)	High-level dynamic input voltage	2			V	
V _{IL(D)}	Low-level dynamic input voltage			0.8	V	

NOTE 4: Characteristics are for surface-mount packages only.

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST C	ONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	112	pF

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_I includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f \leq 3 \ ns$, $t_f \leq 3 \ ns$.
 - D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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